


<b>Search Notes</b>  	<b>Application/Control No.</b>  10552954	<b>Applicant(s)/Patent Under Reexamination</b>  DAVIDSON ET AL.
	<b>Examiner</b>  Nguyen, Huy D	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	405, 412.1, 412.2, 406, 407, 422.1	12/06/2006	HN
	same as above	11/15/2007	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT).See search history printout.	12/06/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT).See search history printout.	11/15/2007	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner